

ESSDERC 2011

ESSDERC 2011, 12-16 Sept. 2011, Helsinki, Finland

Title: Characterization of Large-Scale Non-Uniformities in a 20k TDC/SPAD Array Integrated in a 130nm CMOS Process

Authors: C. Veerappan, J. Richardson, R. Walker, D.-U. Li, M.W. Fishburn, D. Stoppa, F. Borghetti, Y. Maruyama, M. Gersbach, R. K. Henderson, C. Bruschini, and E. Charbon

doi: 10.1109/ESSDERC.2011.6044167